

**Search Notes**

Application/Control No.

10/612,760

Examiner

David E. Martinez

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search see attached	10/14/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	10/14/2006	DM
Inventor Search eDan	10/14/2006	DM
710/62.ccls. 714/786,790,795.ccls. 370/465,355,252.ccls. with keywords and text search	10/14/2006	DM